

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination OKI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0110135	08-2002	Oki et al.	370/412
	B	US-2002/0061028	05-2002	Chao et al.	370/417
	C	US-2002/0039364	04-2002	Kamiya et al.	370/389
	D	US-2002/0057712 A1	05-2002	Moriwaki et al.	370/463
	E	US-2002/0131412	09-2002	Shah et al.	370/390
	F	US-2003/0123468	07-2003	Nong, Ge	370/412
	G	US-2003/0016686	01-2003	Wynne et al.	370/412
	H	US-2004/0081184	04-2004	Magill et al.	370/413
	I	US-2004/0120321	06-2004	Han et al.	370/395.4
	J	US-2005/0152352	07-2005	Jun et al.	370/388
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

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